

## ABSTRACT OF THE DISCLOSURE

Disclosed is a method for performing scan test on a semiconductor integrated circuit including at least two blocks to be tested each capable of performing active functions. The method includes at least the steps  
5 of isolating each of the at least two blocks to be tested exclusively from further blocks; and supplying a plurality of scan clocks each to each of the at least two blocks, in which the plurality of scan clocks each have the phase different from each other. In addition, a semiconductor integrated circuit for use in the method is provided including at least two  
10 blocks to be tested each capable of performing active functions, an isolation unit for isolating each of the at least two blocks to be tested exclusively from further blocks, and an input terminal for inputting a plurality of scan clocks each to each of the at least two blocks, in which each of the at least two blocks is provided with a Core Wrapper  
15 Architecture as the isolation unit, and a Wrapper register included in the Core Wrapper Architecture is configured to be supplied selectively with one of a scan clock and a system clock for the blocks.